

Notice of References Cited	Application/Control No. 10/521,995		Applicant(s)/Patent Under Reexamination SEE ET AL.	
	Examiner SHEELA C. CHAWAN		Art Unit 2624	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,730,495	03-1988	Green, Philip S.	73/620
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
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	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	(Vogel .D. et al., Listed in IDS filed on 11/9/06, "Microdac - a novel 12-15 approach to measure in situ deformation fields of microscopic scale" MICROELECTRON. RELIAB. (UK), MICROELECTRONICS AND RELIABILITY, NO. 11/12, vol. 36, 8 October 1996 (1996-10-08) - 1996, pages 1939-1942).
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.